

## Nidec Read to Exhibit Products at JPCA Show 2015

27/05/2015

We are pleased to inform that Nidec-Read will be exhibiting at JPCA Show 2015, held in Tokyo Big sight, on 3rd-5th June 2015.

This year, we will exhibit Semiconductor package Open/Short inspection system "

GATS-6310" and flexible printed circuit Open/Short inspection system "NRFEIS-3045A".

Not only test systems for PCBs and semiconductor packages but we also would like to introduce our optical inspection systems and automotive test systems. Improved model tester and high precision fixture will be put on the show as well. We believe that we are able to suggest an optimal methodology for each one of you by means of a wide range of our technology.

### Products Line-up

- Semiconductor package test system: "GATS-6310"
- PCB Test System: "STAR REC M6 II W" / "STAR REC M6 II SW"
- 4-wire High-speed and High-accuracy Test System: "R-6510is"
- Optical Inspection System: "RSH-S230T", "RWi-300"
- Fixture, "Coax MEMS probe", "15um Probe Fixture", "Universal Fixture", "MEMS Process line"
- Multi-faced FPC O/S inspection system: "NRFEIS-3045A"
- Data logger correspond with automotive data logging: "Trend Coder"

Venue: Tokyo Big Sight

Period: From June 3 (Wed) to 5 (Fri) , 2015

Booth: 5C-04

Official site: <http://www.jpca-show.com/show2015/en/>